Measurement Report for Device, , , UID 0 -, Channel 0 (2450.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device.	N/A x N/A x N/A		Dipole	

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	2450.000,	7.98	1.86	40.1
HSI ISH			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7733, 2024-02-21	DAE4 Sn1739, 2024-01-23
хххх	2024-Jun-12		

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

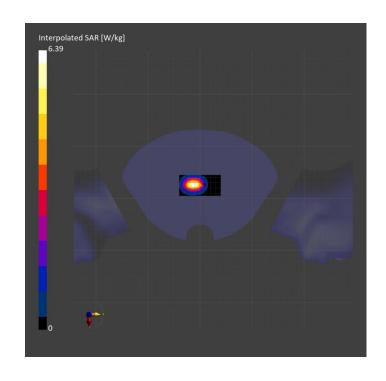
Measurement Results

	Area Scan	Zoom Scan
Date	2024-06-12, 12:15	2024-06-12, 12:24
psSAR1g [W/kg]	4.85	5.04
psSAR10g [W/kg]	2.26	2.33
Power Drift [dB]	0.04	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.6
Dist 3dB Peak [mm]		9.0

Warning(s) / Error(s)

Details Area Scan Zoom Scan

Warning(s) Error(s)



Measurement Report for Device, , , UID 0 -, Channel 0 (5250.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5250.000,	5.64	4.60	35.2
HSI			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7733, 2024-02-21	DAE4 Sn1739, 2024-01-23
хххх	2024-Jun-12		

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

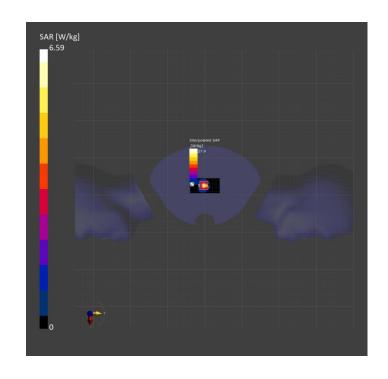
Measurement Results

	Area Scan	Zoom Scan
Date	2024-06-12, 13:01	2024-06-12, 13:11
psSAR1g [W/kg]	6.58	7.23
psSAR10g [W/kg]	1.85	2.15
Power Drift [dB]	0.09	0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.6
Dist 3dB Peak [mm]		7.2

Warning(s) / Error(s)

Details Area Scan Zoom Scan

Warning(s) Error(s)



Measurement Report for Device, , , UID 0 -, Channel 0 (5750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	N/A x N/A x N/A		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	,		CW,	5750.000,	5.05	5.23	36.2
HSL			0	0			

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7733, 2024-02-21	DAE4 Sn1739, 2024-01-23
хххх	2024-Jun-12		

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2024-06-12, 13:25	2024-06-12, 13:35
psSAR1g [W/kg]	6.99	7.92
psSAR10g [W/kg]	2.09	2.31
Power Drift [dB]	0.07	0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.0
Dist 3dB Peak [mm]		7.6

Warning(s) / Error(s)

Details	Area Scan	Zoom Scan

Warning(s) Error(s)

